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October 3-5, 2016, ISBN: 978-1-5090-1393-7/16; DOI: 10.1109/BEC.2016.7743735

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- NOVAK O., JENICEK J., ROZKOVEC M. : "Sequential Test Decompressors with Fast Variable Wide Spreading", [DDECS2016](#) , Kosice, Slovakia, April 2016

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- PFEIFER, P.: "A_mBRAM^s - An Analysis Tool, Method and Framework for Advanced Measurements and Reliability Assessments on Modern Nanoscale FPGAs", 25th International Conference on Field Programmable Logic and Applications ([FP L'15](#)

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 - PFEIFER, P., PLIVA, Z.: "On Utilization of BRAM in FPGA for Advanced Measurements in Mechatronics", 12th International Workshop of Electronics, Control, Measurement, Signals and their application to Mechatronics [ECMSM2015](#) , Liberec, June 2015
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